## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	:	Li, et al.	)	Group Art Unit Unknown
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App. No.	:	Unknown	)	
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Examiner	:	Unknown	)	

### INFORMATION DISCLOSURE STATEMENT

United States Patent and Trademark Office P.O. Box 2327 Arlington, VA 22202

Dear Sir:

Enclosed are copies of PTO-1449 and 892 listing 19 references. These references are of record in related applications No. 09/618,504, filed July 18, 2000 and 09/964,218, filed September 25, 2001. Therefore, copies of the references are not enclosed. This Information Disclosure Statement is being submitted upon filing, and no fee is required in accordance with 37 C.F.R. § 1.97(b)(1).

Identification herein is not an admission that any of the foregoing references are prior art to the above-captioned application.

Respectfully submitted,

KNOBBE, MARTENS, OLSON & BEAR, LLP

Dated: July 1, 2005

Michael S. Okamoto

Registration No. 47,831

Attorney of Record

Customer No. 20,995

(310) 551-3450

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SHEET 1 OF 1





FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE

PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO. MICRON. 198A-198C1DV2 APPLICATION NO. <del>09/618,504</del> unknown

INFORMATION DISCLOSURE STATEMENT BY APPLICANT

(USE SEVERAL SHEETS IF NECESSARY)

APPLICANT S. Li, et al.

FILING DATE July 18, 2000 - Herewith **GROUP** 2018

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FORM PTO-1449

U.S. DEPARTMENT OF COMMERCE

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		Pohm et al., "Experimental and Analytical Properties of 0.2 Micron Wide, Multi-Layer, GMR, Memory Elements", <u>Transactions on Magnetics</u> , Vol. 32, No. 5, September 1996
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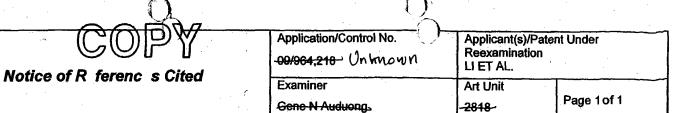
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